

AMENDMENTS TO THE SPECIFICATION

Please replace paragraph [0021] of with the following amended paragraph:

[0021] For a better understanding of the invention, and to show by way of example how the same may be carried into effect, reference is now made to the detailed description of the invention along with the accompanying figures in which corresponding numerals in the different figures refer to corresponding parts and in which:

FIGURE 1 depicts an illustrative data plot for one embodiment of the present invention;

FIGURE 2 depicts another illustrative data plot for one embodiment of the present invention;

FIGURE 3 provides an illustrative example of one embodiment of data analysis according to the present invention; and

FIGURE 4 provides another illustrative example of one embodiment of data analysis according to the present invention[[]; and

FIGURE 5 provides an illustrative example of one embodiment of a data analysis system according to the present invention]].

Please add the following new paragraph after paragraph [0030]:

[0030.1] Thus, by the present invention, a system is provided that analyzes data accuracy – particularly the accuracy of industrial measurement data. Referring now to FIGURE 5, system 500 provides a general illustrative depiction of one embodiment of such a system. System 500 comprises a construct 502 that compiles a plurality of measurements 504 of a primary characteristic, taken from a representative cross-section 506 of a population of devices. The system further comprises a modeling function 508, and a construct 510. Construct 510 determines a variance, from modeling function 508, for each measurement in the plurality of measurements 504, and forms a corresponding plurality of variances 512. A construct 514 evaluates plurality 512 for discontinuities; and a construct